

Kinetic control of catalytic CVD for high quality graphene at low temperatures

Robert S. Weatherup¹, Bruno Dlubak¹, Stephan Hofmann^{1,}*

¹Dept. of Engineering, University of Cambridge, Cambridge CB3 0FA, UK

ABSTRACT

Low temperature ($\sim 600^\circ\text{C}$), scalable chemical vapor deposition of high quality, uniform mono-layer graphene is demonstrated with a mapped Raman 2D/G ratio of >3.2 , D/G ratio ≤ 0.08 and carrier mobilities of $\geq 3000\text{cm}^2\text{V}^{-1}\text{s}^{-1}$ on SiO_2 support. A kinetic growth model for graphene CVD based on flux balances is established, which is well supported by a systematic study of Ni-based polycrystalline catalysts. A finite carbon solubility of the catalyst is thereby a key advantage, as it allows the catalyst bulk to act as a mediating carbon sink while optimized graphene growth occurs by only locally saturating the catalyst surface with carbon. This also enables a route to the controlled formation of Bernal stacked bi- and few-layered graphene. The model is relevant to all catalyst materials and can readily serve as a general process rationale for optimized graphene CVD.

Keywords: Graphene, Chemical vapor deposition (CVD), low temperature, catalyst, Ni, bi-layer, Bernal stacking

*sh315@cam.ac.uk

Chemical vapor deposition (CVD) is the most promising route towards scalable graphene production and integration, key requirements for the commercial exploitation of graphene's unique properties. While progress has been made in achieving graphene CVD over large areas,¹⁻³ the underlying growth mechanisms have yet to be fully understood to enable further process optimization. A key part to the CVD process is the choice of catalyst. Cu is currently the most widely used catalyst material, as it allows a rather error-tolerant window for the formation of mono-layer graphene (MLG) on its surface at high temperatures (>900°C). The prevalent rationale for catalyst choice is thereby based on the carbon solubility: a low carbon solubility, such as for Cu, is thought to be preferable to prevent carbon dissolution and a bulk reservoir effect that would make it difficult to get uniform graphene due to carbon precipitation upon cool-down.⁴ For high (>800°C) temperature CVD with catalysts of higher carbon solubility, such as Ni, it is indeed very challenging to achieve graphene uniformity and layer control.⁵⁻⁷ It should be noted, however, that, in contrast to Cu, Ni is a much better catalyst for (1) the dissociation of typically used carbon precursors and (2) for the formation of a graphitic lattice. Hence Ni can enable a significant reduction in process temperature while maintaining the same graphene quality,⁷ *i.e.* Ni should be a catalyst material of choice for low temperature CVD. This is further motivated by surface science studies exposing Ni(111) single crystals that highlight MLG formation at <750°C and the theoretically almost perfect lattice match between Ni(111) and MLG.^{8,9}

Here we report scalable graphene CVD on Ni-based catalysts at ~600°C with complete monolayer coverage as well as layer control, and show that it is actually possible to achieve an uniformity and quality that has hitherto only been reported for Cu-based CVD at ~1000°C.² We show that the finite carbon solubility of the catalyst bulk is thereby actually a key advantage, in contrast to previous literature which always saw it as undesirable.⁴ We

introduce a relatively simple kinetic growth model which not only shows excellent agreement with our systematic experimental study but, we think, is of general relevance to all catalyst materials and optimized graphene CVD.

RESULTS AND DISCUSSION

Figure 1 shows the uniformity and quality of MLG achieved by low temperature ($\sim 600^\circ\text{C}$) CVD on a Au (10nm) decorated Ni foil (25 μm thickness). A simple one-step CVD process is used, whereby the samples are heated up in H_2 , exposed to an undiluted hydrocarbon and then cooled down in vacuum (see Methods). We note that the Raman and transport measurements are performed after MLG transfer to SiO_2 (300nm) covered Si wafers, *i.e.* include possible degradation incurred during transfer. Figure 1A shows a typical Raman spectrum for our CVD MLG, with a 2D/G ratio of ~ 3.2 and a 2D peak ($\sim 2680\text{ cm}^{-1}$) that is well fitted by a single Lorentzian with a FWHM of $\sim 31\text{ cm}^{-1}$. The D peak ($\sim 1340\text{ cm}^{-1}$) is very small and almost undetectable above the measurement background, suggesting a very low defect density. Little difference is seen compared to a Raman spectrum representative of Cu-catalyzed MLG at 1000°C .¹⁰ Figures 1B-D show an optical image of the same low-temperature MLG as well as $35\times 35\mu\text{m}$ Raman maps of measured 2D/G and D/G intensity ratios. The mapped region has an average 2D/G ratio of ~ 3.4 with $>99.9\%$ of the area having a 2D/G ratio >2 (Fig. 1C). The average D/G ratio is ~ 0.08 , significantly lower compared to recent literature where D/G ratios as high as 0.85 are reported for similar growth temperatures of 600°C .¹¹ 6 contact Hall-geometry devices based on our low temperature CVD MLG (Fig. 1E) give mobilities (on SiO_2 support) $\geq 3000\text{ cm}^2\text{V}^{-1}\text{s}^{-1}$ (with a p doping of $\sim 10^{12}\text{ cm}^{-2}$), equaling the mobilities we measure for high temperature Cu-catalyzed MLG¹⁰ and an order of magnitude larger than for previously reported low-temperature growth at

600°C.¹¹ We note that the measured mobilities are likely to be limited by extrinsic factors such as impurities introduced by the transfer process, adsorbates from the atmosphere and support interactions.^{12,13}

Figure 2 schematically highlights the key points of our kinetic growth model, central to understanding why such high quality and layer control is feasible with Ni-based catalysts at low temperatures. We note that previous literature has typically treated the catalyst bulk as an undesirable reservoir and thereby generally neglected any kinetic effects during exposure.⁴ Figure 2A shows the carbon fluxes essential to graphene CVD, involving precursor dissociation (process 1) and the formation of graphitic layers (process 2). In modeling process (1) we wish to determine the flux of dissociated carbon reaching the catalyst surface, J_S , based on the impingement flux of carbon from the precursor, J_I . J_S will vary with the areal graphene coverage^{14,15} whilst J_I , when modeled within the widely used kinetic theory of gases, will be constant for a given precursor, exposure pressure, and temperature. Here we assume that each graphene layer is not a perfectly impermeable layer but allows a certain proportion, p , of the carbon flux to pass through. J_S can therefore be calculated based on the fractional area coverage, θ_n , of the currently growing n^{th} graphene layer and the carbon flux reaching the catalyst surface through these n layers, $p^n J_I$, and the carbon flux through the $(n-1)$ layers which cover the remaining area, $p^{(n-1)} J_I$, which gives:

$$J_S = \theta_n p^n J_I + (1 - \theta_n) p^{(n-1)} J_I \quad (\text{Eqn 1})$$

We assume thereby that multi-layer graphene grows isothermally during exposure to the carbon precursor⁷ and sequentially in contact with the metal catalyst, *i.e.* a new layer nucleates below a complete surface coverage of the preceding layer.¹⁶ These assumptions will be justified below. We note that exfoliated graphene flakes have been shown to be impermeable to gases,¹⁷ but the carbon leakage can be attributed to the inherent

polycrystallinity of CVD MLG whereby the domain boundaries and other defects offer pathways for carbon to reach the catalyst.

In process (2), the difference between J_S and the diffusive flux of carbon from the surface into the catalyst, J_D , yields the flux of carbon that feeds the growing graphene layer, J_G . J_D can be obtained by consideration of 1-D Fickian diffusion perpendicular to the catalyst surface (see Supporting Information). The catalyst is thereby assumed to have an initially uniform carbon concentration, c_0 , throughout its thickness, and the carbon diffusivity in Ni, D , is taken to only vary with temperature and thus is held constant during the isothermal precursor exposure. For simplicity, we only account here for spatial variations perpendicular to the catalyst surface. Figure 2B illustrates how the calculated graphene coverage θ develops during precursor exposure, and at the same time indicates the carbon distribution in the Ni catalyst at salient stages of the growth. At the start of carbon precursor exposure there is an incubation period in which J_S is matched by J_D , meaning θ remains at zero, but the carbon concentration at the Ni catalyst surface, c_{surf} , gradually increases. For a Ni catalyst of infinite thickness, the variation in c_{surf} with time, t , after introducing the carbon precursor is given by:

$$c_{surf}(t) = c_0 + 2J_I \sqrt{\frac{t}{\pi D}} \quad (\text{Eqn 2})$$

Nucleation of graphene occurs when a certain carbon concentration, c_{nuc} , at the Ni surface is reached, which is supported by our previous observations of a notable incubation time and an interstitial carbon based expansion of the Ni lattice.^{7,15} The incubation time, t_{inc} , is given by:

$$t_{inc} = \frac{\pi D}{4} \left(\frac{c_{nuc} - c_0}{J_I} \right)^2 \quad (\text{Eqn 3})$$

For realistic catalyst films, we consider individual grains that extend throughout the entire catalyst thickness, l , with the back side not exposed. Eqn 1 can be adjusted for this (see

Supporting Information), and a lower limit for t_{inc} is approached for low J_I (with respect to catalyst thickness), where slow filling of the catalyst results in a more uniform distribution of carbon throughout the thickness:

$$t_{inc} \rightarrow \frac{(c_{nuc}-c_0)l}{J_I} \quad (\text{Eqn 4})$$

After nucleation, c_{surf} is held constant at the Ni solubility limit, S , which results in $J_S > J_D$ (*i.e.* $J_G > 0$) and growth proceeds as schematically indicated in Figure 2B. There is a rapid rise in θ following the nucleation of a new graphene layer, as the uncovered area, $(1 - \theta_n)$, is initially large and thus J_S is initially high. The growth rate diminishes as θ_n increases and there is a notable plateau in θ_n prior to the nucleation of the next layer. Here we define this plateau as when >95% coverage of the respective graphene layer is achieved, as shown for the MLG plateau, Δ_{MLG} in Figure 2B. The next layer only nucleates when c_{nuc} is reached at the catalyst surface, and grows when J_S exceed J_D *i.e.* when the gradient of carbon concentration close to the catalyst surface reaches J_D/D , as shown by the inset schematics of the concentration profiles in Figure 2B.

Realistic metal catalysts for scalable graphene CVD are polycrystalline, and this will lead to variations in D perpendicular to the surface, as well as variations in the precursor sticking coefficient (and thus J_S), and c_{nuc} for different Ni grain orientations. These variations ultimately mean that for different Ni grains it will take different times to reach complete coverage. Therefore for a robust MLG growth process, in which uniform coverage over many different catalyst grain orientations can be achieved, a large value of Δ_{MLG} with respect to t_{inc} is desired. We therefore refer to Δ_{MLG}/t_{inc} as a robustness parameter for MLG growth, and we note that Δ_{MLG}/t_{inc} is increased by reducing the leakage, p , or increasing the nucleation barrier for the next layer, c_{nuc} .

We implement our model using a finite-difference Crank-Nicolson method¹⁸ to calculate the variation of θ with t (see Supporting Information) and Figure 3 shows the extracted robustness parameters (Δ_{MLG}/t_{inc}) for different values of J_I and l . This reveals some key trends in particular regarding exposure conditions and optimum catalyst thickness. Assuming for instance $J_I = 10^{18}$ C atoms $m^{-2}s^{-1}$, the 550nm and 25 μ m thick catalyst films become saturated with carbon throughout their thickness before complete MLG coverage is achieved and so Δ_{MLG}/t_{inc} is low, *i.e.* no robust MLG growth can be expected. On the other hand, a higher J_I value of 10^{19} C atoms $m^{-2}s^{-1}$ results in both the 25 μ m and 250 μ m thick catalyst films only being saturated near the catalyst surface during MLG CVD and the corresponding large value of Δ_{MLG}/t_{inc} suggests that robust MLG formation should be possible.

This clearly highlights a distinct difference in growth behavior between a catalyst saturated with carbon throughout its thickness compared to one that is only saturated near the exposed surface. In the latter case, diffusion from the catalyst surface in to the bulk mediates graphene growth and hence gives a broad processing window to achieve layer control by CVD. A lower bound for the catalyst thickness required to grow n layers of graphene without saturating the bulk throughout its thickness, l_{min} , is given by:

$$l_{min} = \frac{DS}{p^n J_I} \quad (\text{Eqn 5})$$

We note that for increasing values of n , the carbon flux to the Ni surface is rapidly reduced and so for conditions similar to those used herein, n will be limited in practice to less than 3-4 layers for realistic exposures. Based on Eqn 5, the lower thickness bound for MLG formation has been plotted in Figure 3 for the different values of J_I , and it corresponds extremely well with the low to high transition of the robustness parameter.

Whether inhomogeneous few-layer graphene (FLG) is formed is determined by p , and the extent to which the Ni bulk is saturated with carbon during growth. If p is high, additional layers will be easily formed by carbon diffusing through existing graphene layers. Whereas even a modest carbon flux through existing graphene will result in the formation of additional graphene layers if the bulk of the catalyst is already well saturated with carbon.

Our model highlights that for controlled graphene CVD it is highly advantageous to tune conditions for the catalyst bulk not to be fully saturated with carbon. This directly relates to an optimum catalyst thickness for given CVD conditions or vice versa. We corroborate our model *via* a systematic growth study of Ni-based graphene CVD in particular looking at Ni catalyst thickness, exposure time, and exposure pressure. As a reference, we use exposures of Ni(25 μ m) foils to C₂H₂ at 10⁻⁵ mbar for 15 mins. Figures 4A-C show that varying the Ni thickness has a significant impact on the growth outcome. The Ni (25 μ m) foil and Ni(250 μ m) slab show uniform MLG coverage across different Ni grains. This corresponds closely to the thicknesses at which robust MLG formation is expected with a J_I value of 10¹⁹ C atoms m⁻²s⁻¹, (as shown in Figure 3) where l_{min} is \sim 9 μ m. In contrast the Ni (\sim 550nm) film shows highly inhomogeneous multi-layer graphene formation for the same CVD conditions. The typical size of each region of constant contrast for the Ni (\sim 550nm) film in Fig. 3A is of the same order as the Ni grain size in these films ($<$ 1 μ m) indicating that the multi-layer graphene coverage is strongly dependent on the underlying Ni grain structure. The fact that for the given CVD conditions only the thicker Ni gives homogeneous MLG is consistent with our kinetic model, which predicts the thin Ni to be saturated with carbon while for the thicker Ni, diffusion into the catalyst bulk mediates the growth of MLG and hence gives robust process conditions.

The carbon diffusion flux into the catalyst bulk J_D is crucial in providing a mediating balance (Fig. 2), but as a result a notable portion of the carbon dissociated at the catalyst surface dissolves into the catalyst bulk. It is important to note that under the described optimized conditions this carbon does not precipitate upon cooling but remains in the catalyst. Figure 5A shows direct evidence for this, whereby after exposing a Ni(250 μ m) slab to reference conditions (Fig. 4C) we removed as-grown MLG and dissolved the Ni to reveal a grey translucent film of amorphous carbon, as confirmed by Raman spectroscopy (see Figure 5A inset). In comparison, figure 5B shows the residual film left for a Ni(250 μ m) slab exposed at a lower C₂H₂ exposure pressure (10⁻⁶mbar, 240mins), which appears much darker and is almost completely opaque. This confirms that for the reference conditions the catalyst is not fully saturated with carbon, and that conditions corresponding to a reduction in J_I result in a more carbon saturated catalyst bulk during growth as predicted by our kinetic model. We note that for standard transfer techniques this dissolved carbon may also be transferred and hence lead to contamination. This motivates the bubbling-based transfer used here.^{19,20} We also performed post-annealing experiments (600°C, 45mins in vacuum) on as-grown samples following a reference C₂H₂ exposure, prior to cooling (see Supporting Information). This resulted in the almost complete disappearance of the MLG from the Ni(250 μ m) slab, which we attribute to carbon dissolution into the catalyst bulk, corresponding to a reduction in the carbon concentration near the catalyst surface as the carbon distribution homogenizes throughout the Ni thickness. For the Ni(25 μ m) foil and Ni(550nm) film the graphene coverage remains unchanged for the post-annealing, indicating the average carbon concentration throughout the catalyst is higher (as the catalyst is thinner) and thus the surface carbon concentration is not reduced adequately during annealing for the graphene to be dissolved. We therefore note that the thermal stability of graphene on Ni depends on the carbon concentration close to the catalyst surface, and not simply temperature.⁹

Figure 2 highlighted the carbon flux balance and, as shown in Figure 3, the precursor impingement flux J_I thereby sets the boundary conditions. For a simple ideal gas approximation, J_I is directly proportional to the carbon precursor partial pressure. For a CVD reactor, this will be more complex dependent for instance on the gas flow regime. Many reactors tend to operate in a transitional or viscous flow regime, where precursor diffusion through a gas boundary layer can be rate limiting. Our experimental study here focuses on low temperatures and relatively low pressures, for which we expect the CVD process not to be mass-transfer limited, but surface reaction controlled. We observe a clear dependence on carbon precursor pressure (see Supporting Information), fully supporting the predictions of our kinetic model. In particular, we find that for instance a tenfold reduction in C_2H_2 pressure relative to our MLG reference conditions, combined with a corresponding increase in exposure time for maintaining the same total catalyst surface exposure, results in inhomogeneous multi-layer graphene formation. This corresponds to the implication of our kinetic model that a reduction in J_I , with the catalyst thickness held constant, leads to a more carbon saturated catalyst bulk during growth (see Fig. 4B) and thus a less robust process (see Figure 3). We note that for significantly higher exposure pressures and/or lower growth temperatures than used here additional graphene layers will form prior to the completion of the first layer. Therefore when applying the model presented, the magnitude of J_S in comparison to the carbon diffusivity at the catalyst surface must be considered to determine whether the assumption of layer-by-layer growth remains valid.

Our previous *in situ* studies of graphene formation on Ni-based catalyst have directly shown that graphene is readily formed isothermally on Ni thin films⁷ and that the relative contribution of carbon precipitation on cooling can be negligible for growth temperatures

<650°C.¹⁵ There is also strong evidence that at the conditions used graphene grows only in direct contact with the catalyst, *i.e.* for multi-layer films additional graphene layers grow underneath the already grown graphene coverage.¹⁶ Looking at the exposure dependence of our growth results (see Supporting Information), we find that, for conditions for which complete MLG coverage is achieved, extended exposure times result in the growth of additional graphene layers. This is consistent with the previous *in situ* evidence and also with our model predictions (as outlined in Fig. 2B), which captures the carbon leakage through domain boundaries in the covering graphene by the parameter p . As previously mentioned, the motivation for the use of Ni is that it is highly catalytically active regarding precursor dissociation. Our systematic *in situ* studies show for instance that at temperatures of around 350°C, C₂H₂ as well as other precursors such as C₆H₆ readily dissociate on Ni. This clearly shows that there is no motivation and no need for an additional plasma excitation for graphene CVD at such low temperatures, unlike suggested in previous literature.^{21,22} Our data herein shows that the overall exposure dependence is very similar for C₆H₆ compared to C₂H₂ as precursor. We note that C₂H₂ is the more reactive carbon source, corresponding to carbon supplied at a higher chemical potential. This is reflected in a lower optimum C₂H₂ pressure compared to C₆H₆ (see Supporting Information).

In order to further optimize the CVD process, our experimental study focuses here on increasing the graphene domain sizes, which should lead to a reduction in the leakage p , and a corresponding increase in Δ_{MLG} giving a more robust process. We previously showed that the graphene nucleation density can be effectively lowered *via* Ni alloying *e.g.* with noble metals.⁷ We clearly confirm here that also for thick Ni foils the thermal evaporation of a thin Au coating allows a significant reduction in MLG nucleation density with a corresponding increase in the lateral size of the MLG domains from $\sim 1\mu\text{m}$ for elemental Ni(25 μm) foils to

>20 μm for Au(25nm)/Ni(25 μm) foils (see Supporting Information). This data also confirms our model predictions, as there is indeed an improvement in the robustness of the process: homogeneous MLG is formed on Au coated Ni foils after C₂H₂ (10⁻⁴ mbar) exposures for 15mins, whilst similar exposures yield inhomogeneous multi-layer graphene coverage on elemental Ni foils. This increase in Δ_{MLG} is crucial (see Fig. 2B) to achieve uniform graphene coverage over many different catalyst grain orientations.

Figure 2B highlights that beyond homogeneous MLG coverage our model also gives conditions for controlled growth of few-layer graphene. Bilayer graphene (BLG) should grow *via* secondary nucleation under a continuous MLG film for increased exposures times and/or precursor pressures. An adequate carbon flux through the existing MLG is important to achieve this (dependent on p) and therefore using a higher exposure pressure should lead to more rapid formation of a second graphene layer. Figure 6A shows, that by increasing the C₂H₂ exposure pressure to 10⁻⁴ mbar and the exposure time to 30mins, BLG islands ~10 μm in dimension form as predicted in the presence of a complete MLG coverage. This extent of growth approximately corresponds to the position marked in Figure 2B. Figure 6B shows Raman spectra for the MLG and BLG regions, confirming the number of layers and good graphitic quality (D/G ratio of ~0.05). Figures 6C,D show the 2D peaks from these Raman spectra fitted with a single Lorentzian (FWHM of 36cm⁻¹) in the case of the MLG, and with four Lorentzian peaks in the case of BLG, which indicates that the BLG is Bernal stacked.²³ Our approach therefore offers a promising new route to forming Bernal stacked bilayers, for which interesting properties have recently been shown including tunable bandgaps.²⁴

CONCLUSIONS

In conclusion, we have shown that through appropriate catalyst and process engineering complete coverage of high quality MLG can be achieved by scalable CVD at $\sim 600^{\circ}\text{C}$. Importantly we demonstrate that continuous, uniform growth is achieved even for polycrystalline catalysts. A finite carbon solubility of the catalyst is thereby a key advantage, as the catalyst bulk acts as a mediating carbon sink that moderates the variations in growth seen for instance for different catalyst grain orientations. Optimized growth is achieved by only locally saturating the catalyst with carbon near the growth surface, which translates into matching the CVD exposure conditions to the catalyst thickness. We note that this diffusion mediated growth does not necessarily require a thick catalyst film and that a suitable carbon sink could be artificially engineered for example by using catalyst alloys or heterostructures containing high carbon solubility and/or stable carbide forming elements. In fact several reports have incidentally made use of such structures and observed robust MLG formation,^{25,26} although this has previously been attributed to a reduction in precipitation on cooling rather than the diffusion moderated isothermal growth we show here. We establish a kinetic growth model for graphene CVD based on carbon flux balances, which is well supported by our systematic study of the parameter space of Ni-based catalysts. We thereby also show a route to the controlled formation of Bernal stacked bi- and few-layered graphene. Our results and model are of general relevance to all catalyst materials, in particular highlighting that, contrary to previous literature, a finite carbon solubility is not necessarily a negative attribute. Our model can readily serve as a general process rationale for optimized graphene CVD.

METHODS

We investigate sputter deposited, polycrystalline Ni films (~550 nm thick, 99.995% purity sputter target) on SiO₂(300nm)/Si substrates, polycrystalline Ni foils (25µm thick, Alfa Aesar 99.99% purity) and polycrystalline Ni slabs (250µm thick, Alfa Aesar 99.994% purity). Au-Ni catalysts are produced by thermal evaporation of Au(0-50nm) directly on top of the Ni catalyst prior to annealing and growth. The samples are annealed [$\sim 600^{\circ}\text{C}$, H₂(1mbar) for 15mins, heated at $\sim 300^{\circ}\text{C}/\text{min}$], exposed to hydrocarbons [$\sim 600^{\circ}\text{C}$, C₂H₂(10^{-6} - 10^{-3} mbar) or C₆H₆(10^{-4} - 10^{-3} mbar)], and then cooled [in vacuum at $\sim 100^{\circ}\text{C}/\text{min}$] in a custom-built cold-wall reactor [base pressures 5×10^{-7} mbar]. The annealing stage is found to promote grain growth of the catalyst films and ensure sufficient alloying for the Au-Ni catalysts.

Samples are characterized *ex situ*, either as-grown using scanning electron microscopy (SEM, FEI Philips XL30s/Zeiss SigmaVP, 1kV) or after transfer of the M-/FLG films to SiO₂(300nm)/Si substrates, using optical microscopy, and Raman spectroscopy (Renishaw Raman InVia Microscope, 532nm excitation). Regions not covered with graphene appear brighter on average in the SEM micrographs, as a result of the higher secondary electron yield of Ni compared to MLG,²⁷ whilst increasingly thick FLG layers appear darker. There are also significant variations in contrast associated with Electron Channeling Contrast arising from the different grain orientations in the underlying polycrystalline Ni foils.²⁸ These different contrast mechanisms can generally be distinguished by the shape and size of the features they are associated with, which has been further corroborated by M-/FLG transfers to SiO₂(300nm)/Si substrates. Transfer is carried out using polymethylmethacrylate (PMMA) to support the M-/FLG films and an electrolysis based bubbling technique^{19,20} with the PMMA/graphene/Ni sample as the cathode and a Pt wire anode in a NaOH (1M) aqueous solution. Following removal of the catalyst layer, the PMMA supported M-/FLG films are rinsed in DI water and transferred to SiO₂(300nm)/Si substrates, and the PMMA is then

dissolved away using acetone. This process leaves the catalyst film intact,^{19,20} and optical microscopy and low magnification TEM of the transferred graphene, show no significant metal remnants. To isolate the residual carbon left in the intact Ni films, wet etching of the catalyst layer in a FeCl₃ (1M) aqueous solution was used to remove the Ni.

Electrical measurements are performed at room temperature using Hall-bar devices fabricated by e-beam lithography on transferred MLG (see Figure 1B). The MLG is patterned by an O₂ plasma etch and then Ti/Au contacts are evaporated on top.

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SUPPORTING INFORMATION

Description of the derivation of the kinetic model, and additional experimental data relating to the systematic growth study of Ni-based polycrystalline catalysts. This material is available free of charge *via* the Internet at <http://pubs.acs.org>.

FIGURES

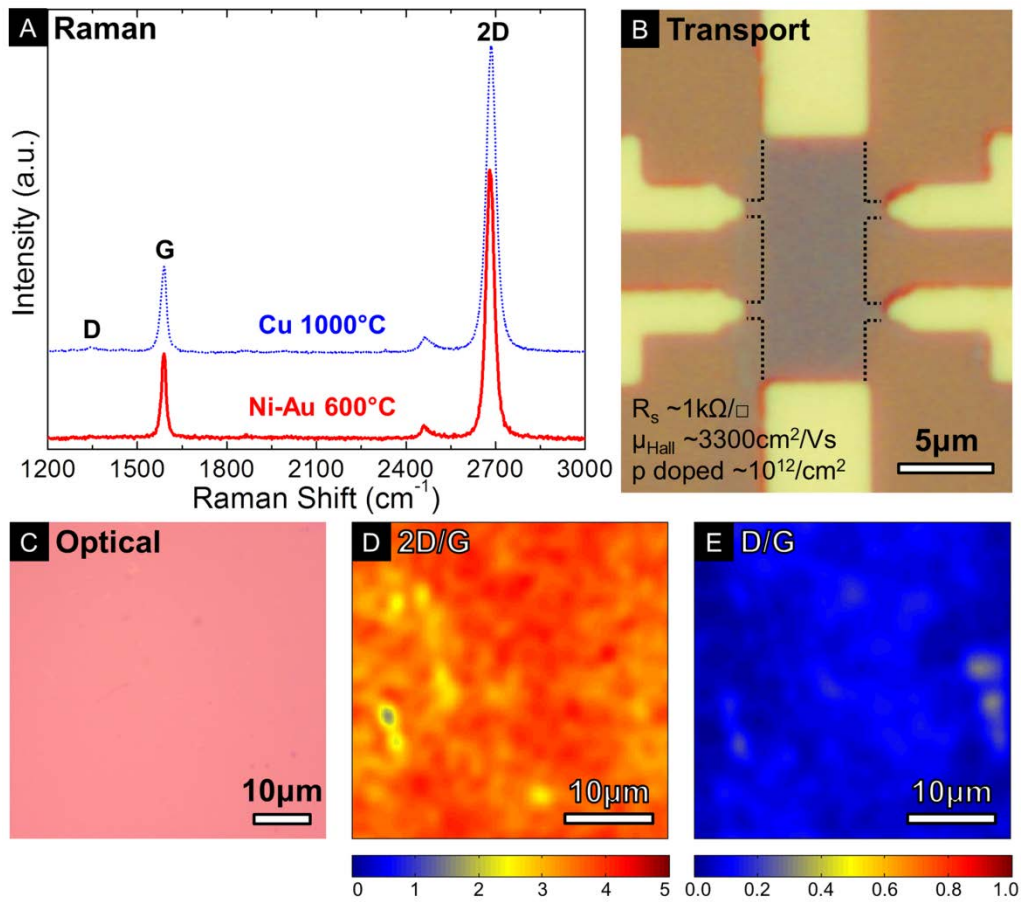


Figure 1 (A) Raman spectra of MLG grown on Au(10nm)/Ni(25 μ m) by $C_6H_6(10^{-3}$ mbar) exposure for 30mins at $\sim 600^\circ C$ and subsequently transferred to Si/SiO₂(300nm) using bubbling transfer method, and a reference spectrum of MLG grown on Cu by CH₄ exposure at 1000 $^\circ C$ from Kidambi *et al.*¹⁰ (B) Optical Micrograph of Hall bar device fabricated from the transferred MLG grown on Au(10nm)/Ni(25 μ m) using e-beam lithography, O₂ plasma etching, and thermally evaporated Ti/Au contacts. (C) Optical Micrograph of as-transferred MLG grown on Au(10nm)/Ni(25 μ m). (D,E) Corresponding Raman maps of 2D/G peak intensity (D) and D/G peak intensity (E).

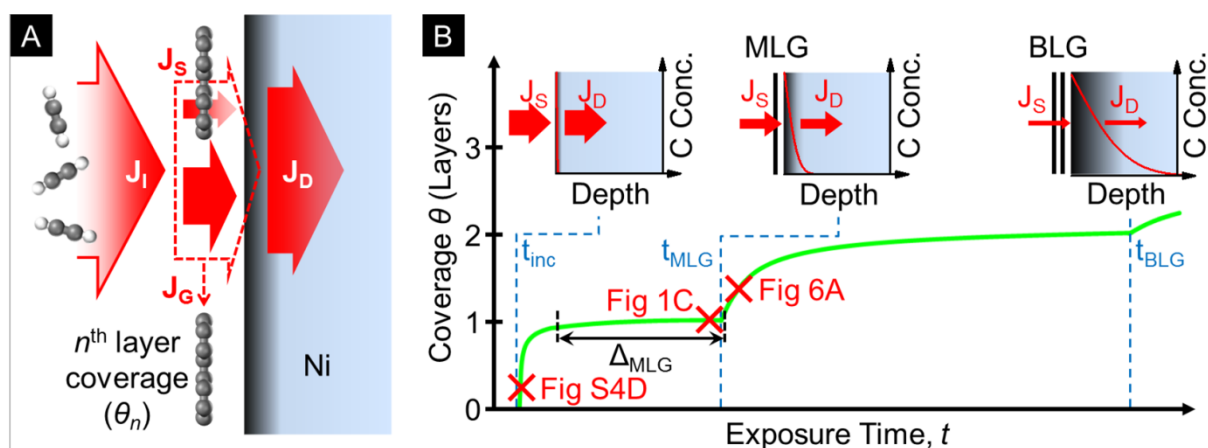


Figure 2 (A) Schematic showing the relationship between the significant carbon fluxes accounted for in the graphene growth model. The carbon fluxes associated with the precursor impingement, J_I , dissociation at the catalyst surface, J_S , diffusion into the catalyst, J_D , and graphene formation, J_G , are considered. (B) Schematic indicating how graphene coverage evolves for a semi-infinite catalyst based on the growth model developed, with insets indicating the carbon concentration throughout the catalyst film at various stages of the growth. Red crosses indicate the approximate stages of growth which Figures S1, 1C, 4A correspond to.

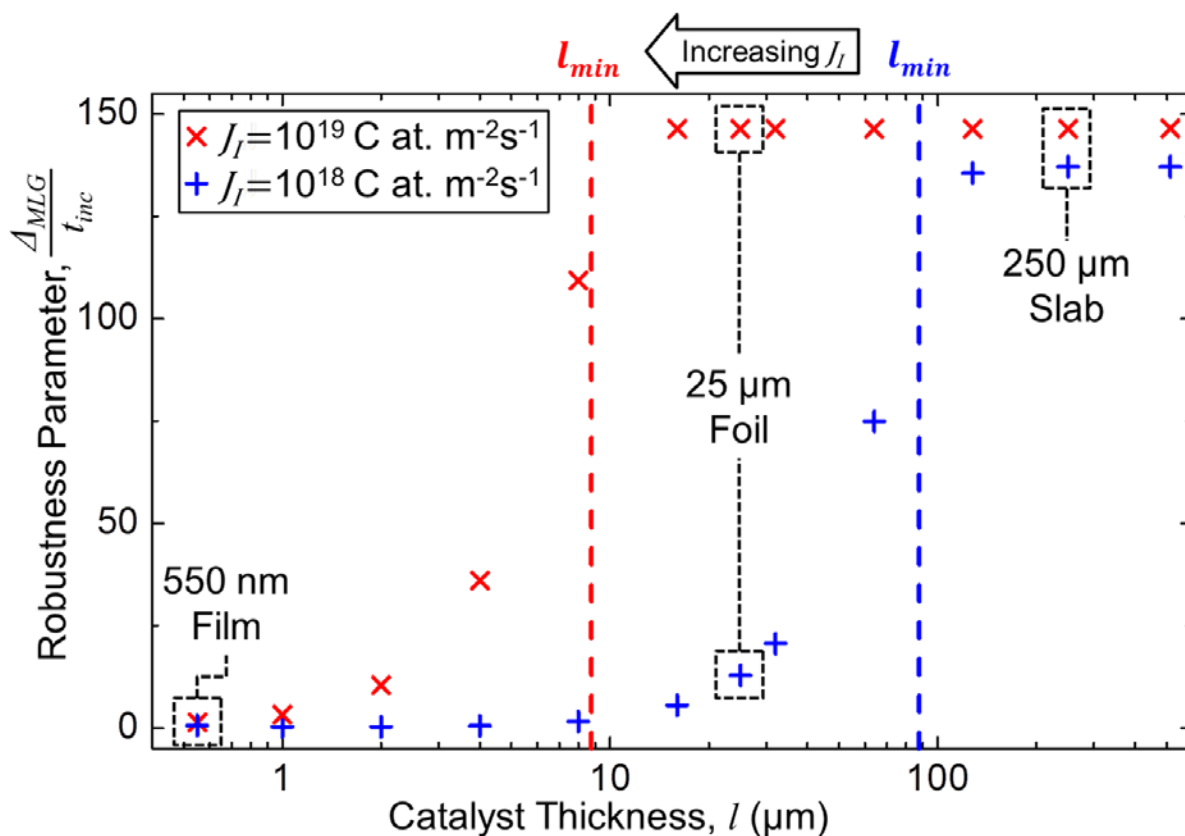


Figure 3 Calculated relationship between catalyst thicknesses and the MLG formation robustness parameter (the ratio between MLG plateau width and incubation time, Δ_{MLG}/t_{inc}) for different carbon impingement fluxes (J_I). A larger value of Δ_{MLG}/t_{inc} indicates a more robust process for MLG formation over large areas. Data points corresponding to the conditions used in our experimental study are labeled. The lower bounds for the catalyst thickness required to avoid saturating the catalyst throughout its thickness during MLG formation (l_{min}) are also indicated for the different values of J_I . The data is obtained using the kinetic model presented and is implemented using a finite-difference Crank-Nicolson method (see Supporting Information) with the value of p fixed at 0.05 and values of S and D calculated for a growth temperature of 600°C, based on the results of Lander *et al.*²⁹

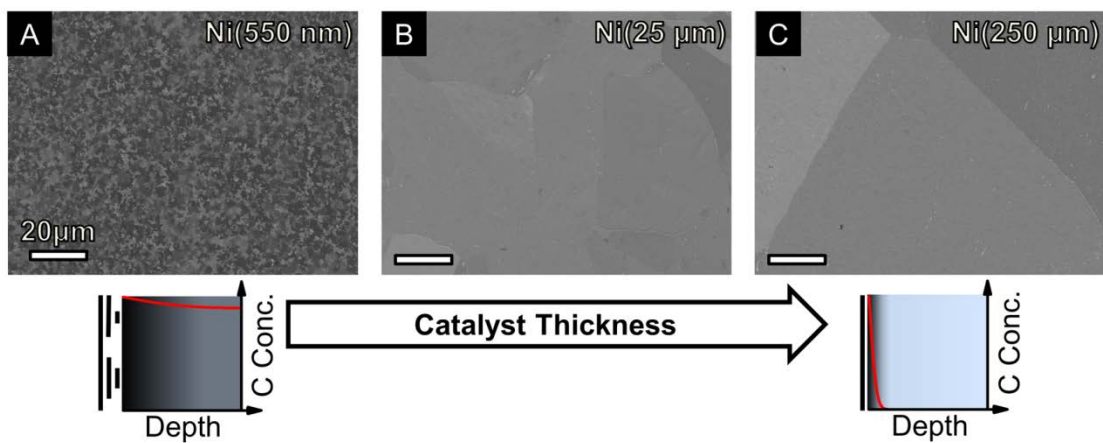


Figure 4 SEM micrographs of elemental Ni catalyst surfaces following C_2H_2 (10^{-5} mbar) exposures at $\sim 600^\circ C$ for 15 mins on for Ni catalyst thickness of 550 nm (A), 25 μm (B), and 250 μm (C). All scale bars are 20 μm .

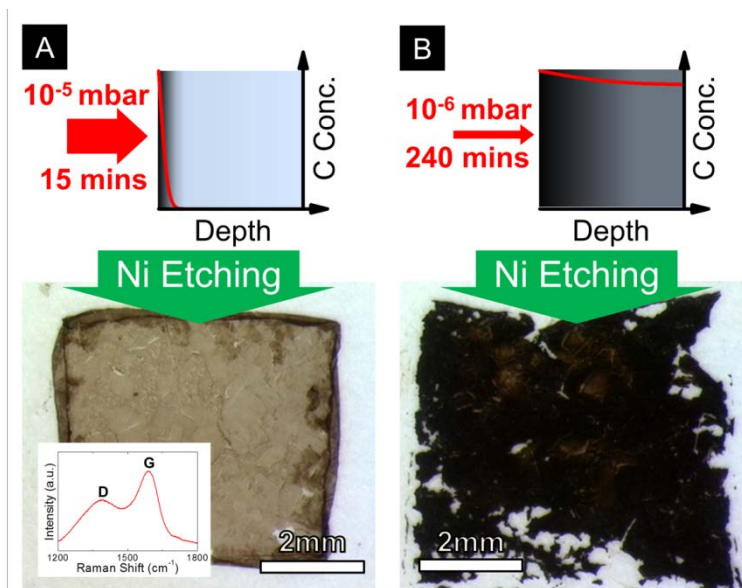


Figure 5 Optical Micrographs of residual material following removal of as-grown MLG by bubbling transfer and subsequent Ni removal by etching with a 1M $FeCl_3$ aqueous solution for Ni(250 μ m) slabs exposed to (A) $C_2H_2(10^{-5}$ mbar) for 15mins at $\sim 600^\circ C$ [inset with corresponding Raman spectrum] and (B) $C_2H_2(10^{-6}$ mbar) for 240mins at $\sim 600^\circ C$. All scale bars are 2mm. Sketches representative of the different extent of carbon filling of the catalysts are also shown.

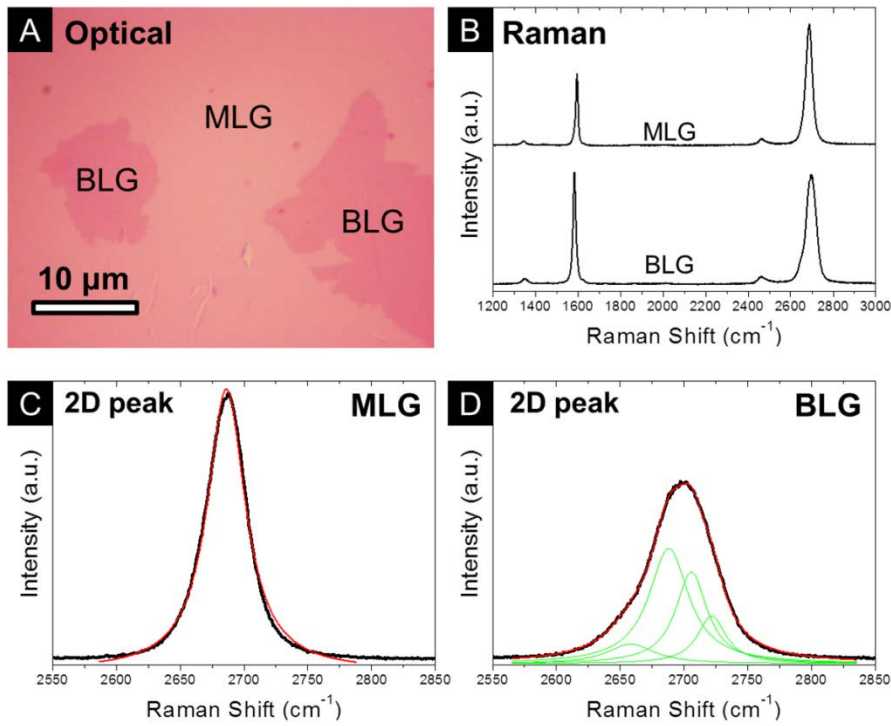


Figure 6 (A) Optical Micrograph of M-/BLG grown on Au(25nm)/Ni(25μm) by C₂H₂(10⁻⁴mbar) exposure for 30mins at ~600°C and subsequently transferred to Si/SiO₂(300nm) using bubbling transfer method. (B) Raman spectra corresponding to MLG and BLG regions and the respective 2D peaks fitted with a single Lorentzian peak for MLG (C) and four Lorentzians for BLG (D).

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